

U.S. Patent Application Serial No. 09/926,347
Amendment dated August 4, 2003
Reply to Office Action of February 3, 2003

IN THE SPECIFICATION:

Please amend the specification as follows:

Paragraph beginning at page 13, line 9 has been amended as follows:

While, in the above embodiment, the cells 12a are used only to detect the signal from the conductive pattern 61, they may be used to supply an inspection signal to the conductive pattern 61 in a non-contact manner as a substrate for the probe 52 (for example, Japanese Patent Application No. ~~2000-333732~~ 2000-33732 filed by the applicant), in addition to the above function.

Paragraph beginning at page 14, line 13 has been amended as follows:

As seen from Fig. 18 showing the interior structure of the probe 204, the probe 204 comprises a hollow cylindrical mounted shank ~~204~~ 204a, a probe body 204b, a spring 204c housed in the mounted shank 204a. The probe body 204b is movable or resiliently displaceable vertically to the mounted shank 204a against the bias force of the spring 204c. Thus, the tip of the probe body 204b may keep its contact to the external electrode 2e even if the inspection apparatus A is inclined.